Stable and low photovoltage loss perovskite solar cells by multifunctional

passivation

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Abstract: Metal halide perovskite solar cells (PSCs) have demonstrated high power conversion efficiency (PCE), while further efficiency enhancement requires reducing 49 bandgap-voltage offset (*W*_{OC}) and non-radiative recombination photovoltage loss 50 ($\Delta V_{\text{OC,nr}}$). Here, we report an effective approach in reducing the photovoltage loss through the simultaneous (a) internal bulk defects and (b) dimensionally graded 2D perovskite interface defects passivation. Through this Dimensionally Graded 53 Perovskite Formation (DGPF) approach, an open-circuit voltage (V_{OC}) of 1.24 V was obtained with a champion PCE of 21.54% in a 1.63 electron volts (eV) perovskite 55 system (maximum $V_{\text{OC}}=1.25$ V, $W_{\text{OC}}=0.38$ V, and $\Delta V_{\text{OC,nr}}=0.10$ V); we further 56 decreased W_{OC} to 0.326 V in a 1.53 eV perovskite system with a V_{OC} of 1.21 V and a PCE of 23.78% (certified 23.09%). This approach is equally effective in achieving 58 low W_{OC} ($\Delta V_{OC,nr}$) in 1.56 eV and 1.73 eV PSC systems, and further leads to significantly improved operational stability of PSCs.

Introduction

Perovskite solar cells (PSCs) based on three-dimensional (3D) perovskite absorbers have achieved rapid progress with power conversion efficiency (PCE) of over 25%, due to the outstanding optoelectronic properties of 3D perovskites. Nevertheless, their poor stability nature, particularly the susceptibility to humid environments, lack of thermal stability, and light-soaking degradation, become a major shortcoming that limits their further practical application.

68 As PSCs' band gap-voltage offset (W_{OC}) is still higher than GaAs $(W_{OC}$ -0.3 V) 69 cells ¹, reducing the W_{OC} and pushing the PSCs' V_{OC} towards the Schottky-Queisser *V*OC limit (radiative recombination loss only) is of great significance in boosting the PCE as well as understanding the fundamental science $2, 3, 4, 5, 6$. Several studies have shown that non-radiative recombination via defects at the interfaces between perovskite and charge transport layers are the main sources of voltage losses for $PSCs^{7, 8, 9}$. Strategies such as surface passivation or processing additives have been explored to minimize the non-radiative recombination losses at interfaces and thus to

76 improve the V_{OC} of devices^{10, 11}. For example, surfaces and grain boundaries with potassium passivation was shown to enable substantial mitigation of non-radiative 78 recombination losses ($\Delta V_{OC, \text{nr}}$), pushing the V_{OC} up to 1.17 V with a low W_{OC} of 0.39 $V (\Delta V_{OC,nr} = 0.11V)$ for a 1.56-eV-bandgap 3D perovskite system. However, there are still substantial non-radiative losses causing from trap states within the perovskite 81 bulk film, which limits the performance and stability of perovskite devices¹². In addition, the energy level alignment at the interface is also a key factor for minimizing interfacial non-radiative recombination, which requires careful interface μ design¹³. Thus, simultaneous interface and bulk trap passivation strategy as well as interface engineering are required to further reach the full thermodynamic potential of V_{OC} .

In this work, we introduced a multifunctional (bulk and interface) 2D perovskite passivation approach and graded interface design to significantly reduce PSC photovoltage loss and enhance device stability. N-butylammonium bromide (BABr) was first coated on top of the 3D perovskite film, and through thermal driving, we simultaneously achieved relatively uniform distribution of self-passivated 2D/3D perovskites in the bulk, covered by graded mixed dimensional, wider bandgap 2D perovskite layers. We name it as Dimensionally Graded Perovskite Formation (DGPF) approach. This multifunctional approach effectively suppresses the non-radiative recombination loss in both the bulk and the interface of perovskite. Via this DGPF technique, we demonstrate a hysteresis-free maximum PCE of 21.54% with a high *V*_{OC} of 1.24 V in a 1.63 eV perovskite system, and the *W*_{OC} is only 0.39 V, equivalent 98 to non-radiative recombination V_{OC} loss $(\Delta V_{\text{OC,nr}})$ of only 0.11 V. Particularly, 99 minimum W_{OC} of 0.38 V and $\Delta V_{\text{OC,nr}}$ of 0.10 V was achieved in a 20.15% PCE device. 100 We further decrease the W_{OC} as low as 0.326 V in a ~1.53 eV perovskite system $(\Delta V_{\text{OC,nr}} = 74 \text{ mV})$, with a maximum *V*_{OC} of 1.21 V and champion PCE of 23.78% (certified PCE of 23.09%). The DGPF approach is also validated by examining hybrid 103 PSCs with bandgaps of 1.56 eV and 1.73 eV, where very low $W_{OC} (\Delta V_{OC,nr})$ and high *V*_{OC} were both achieved. At the same time, the 2D perovskite components in the bulk and at the interface provide superb stability under illumination, ensuring the DGPF

device can maintain 91% of its initial efficiency over 500 h under 1-sun illumination at MPP condition.

Fig. 1a shows the schematic illustration of our DGPF method, and Fig. 1b shows the cross-sectional high-resolution transmission electron microscope (HRTEM) of the 110 DGPF perovskite film deposited on the $SnO₂-coated ITO$ substrate, which can verify the homogeneity of 2D perovskite layer on the top of 3D perovskite films 14 . The 3D perovskite films with a quaternary-cation of RbCsMAFA was formed by using the 113 antisolvent-assisted one-step method , which has demonstrated state-of-the-art 114 device performances in several studies from EPFL team^{15, 16, 17}. The quaternary-cation 115 perovskite system has shown not only high efficiency, but also higher V_{OC} (1.16-1.18) 116 V) than ternary-cation (~1.13 V) counterpart (both are ~1.63 eV bandgap) ^{15, 16, 17}. The detailed fabrication method of the device is given in the Experimental Section. Here, to form a mixed 2D/3D perovskite heterojunction films, long-chain n-Butylammonium bromide (BABr) molecules were first dissolved in isopropyl alcohol (IPA) with different concentrations, and then directly spin-coated to form a thin film on top of the as-prepared 3D RbCsMAFA perovskite films, which was followed by thermal annealing at 100℃ for 10 min. This approach leads to perovskite vertical composition distribution evidenced below.

To investigate the distribution of ions inside the perovskite films after introducing BABr, we conducted time-of-flight secondary ion mass spectrometry (ToF–SIMS) measurement on the DGPF perovskite films. ToF-SIMS depth profile shown in Fig. 127 1c reveals that a gradient distribution of $BA⁺$ with the initial sputtering time, which indicates the ultrathin 2D perovskite film was formed at the surface of 3D perovskite layer. In the bulk (originally pure 3D) perovskite film, we now observe a relatively 130 uniform distribution of BA^+ with an over 2-orders lower intensity compared with the $BA⁺$ on the surface, indicating a clear diffusion process. Therefore, it is evident that the bulk film contains both 3D and 2D perovskite with an increasing 2D concentration towards the surface. Owing to the gradient distribution of BA^+ , the layer number (n) of the 2D perovskites might increase from the surface to the bulk, creating a tendency of bandgap narrowing (as illustrated in Fig. 1a and Supplementary Fig. 10b).

Grazing-incidence wide-angle X-ray scattering (GIWAXS) technique was carried 137 out to study the crystal orientation of the control and mixed DGFP perovskite films 18 . The scattering patterns of perovskite films with various concentrations of BABr are shown in Fig. 2a. The corresponding radial intensity profiles averaged over the whole images are presented in Fig. 2b. The standard pure 3D perovskite film displays uniform diffraction rings, indicating the formation of perovskite polycrystals with randomly oriented cubic structure. For the perovskite films with the BABr 143 post-treatment, sharp diffraction peaks emerged at $q = 0.32$, 0.64, and 0.96 $^{-1}$ along 144 the q_z direction (Fig. 2c), which are indexed as (020), (040), (060) planes of layered 2D perovskite crystals parallel to the substrate with a layer spacing of \sim 20 (n=2)¹⁹. The parallel 2D perovskite orientation is surprising, as it is commonly considered to be unfavored for the overall vertical charge transport in solar cell devices. However, the high efficiency PSC in this study indicates that the 2D perovskite layer with relatively larger bandgap is thin enough for carrier transport, and can act as an effective electron blocking layer to suppress the interfacial charge recombination. The 151 BABr GIWAXS peak appeared at $q_z = 0.41$ ⁻¹ in the pure BABr film 152 (Supplementary Fig. 1a) and the excessive PbI₂ peak appeared at $q_z = 0.92$ ⁻¹ in the 3D perovskite film were both absent, suggesting that 2D perovskite layers are partially formed from the reaction of BABr with the excessive PbI2. When the concentration of BABr increases, the 2D perovskite peaks become more intensive, as the higher order (080) peak appears with the 5 mg/ml BABr treatment.

To provide more detailed evidence of the graded 2D perovskite from the surface to the bulk, we conducted GIWAXS analysis at different X-ray incident angles to elucidate the vertical structure of the surface and internal perovskite layers with depth-dependent characterization as shown in Supplementary Fig. 2. The structure information of perovskite film surface was recorded at a small incident angle of 0.1˚, which shows the formation of 2D perovskite layer with n=2 only. When the angle of incidence was increased to 0.3˚, we can clearly observed some additional diffraction peaks, which are assigned to be the (0k0) plane of 2D perovskite with n=3. With increasing the incident angle and penetration depth, the diffraction peak intensity of 2D perovskite with n=2, 3 gradually increased. We can also clearly distinguish the (222) plane of 2D perovskite with n=2, 3, and 4 at an incident angle of 1˚. Thus, the depth-dependent GIWAXS results are in good agreement with our hypothesis of graded top 2D perovskite layers with increased n values for top-down distribution. To further evaluate the structural property of the DGPF perovskite films, we performed high-resolution transmission electron microscope (HRTEM) measurement with focused ion beam (FIB) lift-out technique shown in Supplementary Fig. 3, which can offer the chance to probe the crystal structure throughout the perovskite film. Here, we selected two regions (region 1 and 2), which correspond to the top surface and bulk, respectively. The region 1 (top surface) shows lattice fringes with characteristic 176 d-spacing of 13 Å, which can be ascribed to 2D perovskite phases with $n=1$. At region 2 (bulk film), we can observe the characteristic d-spacing of 3D perovskite phase (3.2 178 Å). Besides, it is worth noting that 2D perovskite phases with $n=2$ and 3 were embedded within 3D perovskite phases, which may probably located at the grain boundary.

The influence of the annealing time on the perovskite film was also investigated, as shown in Supplementary Fig. 1. The 2D perovskite signals remain almost the same for the samples with and without annealing, whereas, the 3D perovskite signals become stronger with longer annealing time. The diffraction peaks shift towards 185 larger q values, indicating a slight lattice contraction²⁰. It is attributed to the 186 substitution of the relatively larger I[−] ions with the smaller Br[−] ions in 3D perovskite crystals. The longer the annealing time, the more BABr diffused into the bulk film, causing larger lattice contraction, consistent with the ToF-SIMS results. Therefore, as 189 illustrated in Fig. 2d, upon BABr post-treatment, BA^+ and Br^- ions tend to fill the vacancies at grain boundaries of 3D perovskite due to the strong reactivity of 191 introduced BA^+ and Br^- ions with existed dangling bonds²¹. In this case, 2D perovskite phases are most likely to form at the grain boundaries surrounding the 3D perovskite phases. The 2D perovskite will heal and passivate the 3D perovskite defects, significantly reduce the non-radiative recombination, which is in agreement 195 with the observed lower V_{OC} loss presented in the following.

Perovskite film morphology is another critical factor for photovoltaic performance. Top-view scanning electron microscope (SEM) images and atomic force microscopy (AFM) images of control and DGPF perovskite films are shown in Fig. 2e. The morphology of the control RbCsMAFA perovskite film is uniform and compact 200 with well-crystallized grains, which is in good agreement with previous report . With BABr treatment, an obvious grain coarsening process was observed, i.e., the original small perovskite grains were merged into large ones via a thermodynamically 203 spontaneous Ostwald ripening process . We expected that the BABr molecules would gradually penetrate into the existing 3D perovskite crystalline structure, resulting in the formation of thin 2D perovskite phases on the top and the bulk of mixed 2D/3D perovskites film. When a low concentration of BABr solution was used (1 mg/ml or 2 mg/ml), we observe both large and small grains. It is reasonable to expect that in the low concentration cases, the amount of BABr is not enough for recrystallizing all the small-grain-sized 3D perovskite crystals. With further increase of the BABr concentration to 5 mg/ml, the surface morphology became smoother with uniformly distributed grain sizes.

The photovoltaic devices were fabricated using Spiro-OMeTAD as hole selective layer (HSL) and Au as counter electrode. The current density–voltage (*J–V*) curves of the champion control and DGPF PSCs are shown in Fig. 3a. The control RbCsMAFA-based planar PSC device shows a decent champion PCE of 19.61% with 216 a short-circuit current density $(J_{\rm SC})$ of 22.25 mA cm⁻², a $V_{\rm OC}$ of 1.161 V, and a fill 217 factor (FF) of 75.92%. The V_{OC} and J_{SC} are very close to EPFL reports on mesoporous PSCs, while the FF is lower (0.76 vs. 0.81). After BABr treatment, the DGPF PSC exhibits clear performance enhancement, yields a champion PCE of 20.24% when 220 using 1 mg/ml BABr, and 21.54% when using 2 mg/ml BABr, with an impressive V_{OC} of 1.24 V (Supplementary Fig. 4). We fabricated 20 devices in each condition, and the detailed statistical analysis is summarized in Supplementary Table 4. The statistics of two types of devices (control and DGPF PSCs @2 mg/ml BABr) is shown in Supplementary Fig. 5, which indicates good reproducibility in DGPF PSCs with an 225 improved PCE of 20.38% (± 0.38 %) on average compares to 18.80% (± 0.31 %) in 226 control PSCs. A much enhanced average V_{OC} of 1.22 V (\pm 0.02V) in the DGPF PSC, 227 compares to 1.15 V $(\pm 0.02V)$ in pure 3D PSCs, is the major factor contributing to the 228 overall efficiency enhancement. Considering the almost same optical bandgap for the 229 control and DGPF perovskite films, the driving force of high V_{OC} values with a small 230 *W*_{OC} for the DGPF PSCs are of great interest.

The external quantum efficiency (EQE) data of PSCs with different BABr conditions are shown in Supplementary Fig. 4b. As expected, the EQE spectrum is softly blue-shifted when incorporating BABr, which is very small and do not lead to 234 the *J_{SC}* reduction. We observed better photo response in the long wavelength range for the devices treated with BABr solutions, which may originate from enhanced charge 236 transports 23 . For the RbCsMAFA system, when using the BABr solution with an optimized concentration of 2 mg/ml, the 21.54% PCE cell achieved is also hysteresis-free, and the stabilized PCE is 21.27%, as shown in Fig. 3a and Supplementary Fig. 6. Here, we also compared some results of PSCs with over 21% 240 PCE, where the *W*_{OC} varies from 0.39 to 0.48 V, and our DGPF device demonstrated a z41 record V_{OC} among them (Supplementary Fig. 7 and Table 3)^{15, 24}.

242 To understand the fundamental of the high V_{OC} in these PSCs in a quantitative manner, the accurate determination of perovskite bandgap is critical. As shown in Supplementary Fig. 8, the determination of optical bandgaps was conducted in two widely recognized methods: (a) Using the maximum point of the derivative of the EQE spectra (i.e. $dEQE/dE$)²⁵, and (b) Tauc plot method)²⁶. The E_g values from the two methods agree very well.

248 We first exam the electroluminescence (EL) efficiency. The reciprocity relation 249 can describe the relationship between the photovoltaic quantum efficiency (EQE_{PV}) 250 and the external quantum efficiency of the electroluminescence (EQE) , which can 251 be used to quantify the V_{OC} loss in photovoltaic devices 27 . According to Rau, 252 $\Phi_{EL}(E) = \varphi_{BB}(E)EQE_{PV}(E) \left[\exp\left(\frac{qV}{kT}\right) - 1 \right]$, where $\varphi_{BB}(E)$ is the black body emission flux density, the $\Phi_{EL}(E)$ is the EL spectral photon flux $(\Phi_{EL}(E))$ 254 $\frac{J_{inj}(V)}{q}EQE_{EL}(E)$, and $J_{inj}(V)$ is the injected current. As shown in Fig. 3b, the

255 extracted EQE_{PV} exhibited a nearly exact dependence on energy as the measured 256 EQE_{PV}, implying the reciprocity relations hold. Herein, we identify the origins of 257 increased open-circuit voltage in DGPF PSCs by quantifying the dominating 258 recombination mechanisms. The first term $V_{OC,rad}$ describes the radiative limit of V_{OC} , which is determined by $V_{OC,rad} = \frac{kT}{q} \ln \left[\frac{J_{SC}}{\int_0^\infty EQ E_{PV}(E)\varphi_{BB}(E)dE} \right]$ 259 V_{OC} , which is determined by $V_{\text{OC,rad}} = \frac{kT}{s} \ln \left| \frac{f_{\text{SC}}}{f_{\text{OC,rad}}} \right| \left| \frac{f_{\text{SC}}}{f_{\text{DC}}}\right| \left| \frac{f_{\text{DC}}}{f_{\text{DC}}}\right| \left| \frac{f_{\text{DC}}}{f_{\text{DC}}}\right| \left| \frac{f_{\text{DC}}}{f_{\text{DC}}}\right| \left| \frac{f_{\text{DC}}}{f_{\text{DC}}}\right| \left| \frac{f_{\text{DC}}}{f_{\$ 260 calculated $V_{OC,rad}$ is 1.35 V for both reference control and DGPF perovskite devices, 261 both with almost the same 1.63 eV bandgap 28 . Therefore, the difference in the 262 non-radiative recombination losses is the source of V_{OC} enhancement. We then 263 quantify the second term non-radiative recombination voltage loss $(\Delta V_{\text{OC,nr}})$, which in 264 principle can be estimated from the measured EQE_{EL} , with the relationship of 265 $\Delta V_{oc,nr} = V_{oc,rad} - V_{oc} = -\frac{kT}{q} \ln EQE_{EL}$. An EQE_{EL} of 0.85% was measured for a 266 DGPF PSC device under LED mode with forward bias current density of 22.22 $mA/cm²$ (Fig. 3c). This external EL quantum efficiency is very close that of the most efficient silicon solar cell $(-0.5\%)^{29}$. This is also one of the highest values obtained in PSCs. The 0.85% EQE_{EL} corresponds to a $\Delta V_{\text{OC,nr}}$ of 0.12 V ^{15, 30}, which agree well 270 with the device parameter (V_{OC} =1.23 V for the tested device). For the champion 271 efficiency device with a V_{OC} of 1.24 V, the EQE_{EL} should be higher, and the $\Delta V_{\text{OC,nr}}$ 272 will be 0.11 V. The maximum V_{OC} of 1.25 V with 20.15% PCE for the DGPF PSC 273 device indicates a 100 mV $\Delta V_{\text{OC,nr}}$ (Supplementary Fig. 9). On the other hand, the 274 control PSC has a V_{OC} of 1.16 V. Under the forward bias LED mode with the same 275 injected current density of 22.22 mA/cm², the PSC delivers an EQE_{EL} of 0.065% 276 (corresponding to $\Delta V_{\text{OC,nr}}$ of 0.19 V from the equation), which also agrees well with 277 the device V_{OC} loss analysis. The extraordinarily low non-radiative recombination 278 losses in DGPF PSCs are the dominating reason behind the high V_{OC} as well as the 279 high efficiencies in these PSC devices. Generally, these non-radiative recombination 280 losses arise from defects (charge carrier traps) either in the bulk photovoltaic 281 materials or at the interfaces.

282 The ultraviolet photoelectron spectroscopy (UPS) on 3D perovskite films with 283 different BABr concentrations are performed to understand electronic properties of 284 the films. Supplementary Fig. 10a shows the cutoff energy (E_{cutoff}) in high binding energy region and valance band (VB) with respect to vacuum level derived from UPS 286 spectra. With the increase of BABr concentration, the E_{cutoff} shifts to higher binding energy, indicating the ion-exchange induced 3D to 2D phase transition can reduce the 288 Fermi level of RbCsMAFA . The valence band edges determined by the linear portion in low binding energy region for 0-BABr, 1-BABr, 2-BABr, and 5-BABr are located at 5.86, 5.80, 5.74, and, 5.70 eV, respectively. Here, to mimic a similar situation, a thinner ~100 nm 3D perovskite films with and without BABr treatment are used to enhance signal-noise-ratio. The absorption spectra of the thin control and DGPF perovskite films are shown in Supplementary Fig. 11. It is noteworthy that the absorption peak could be observed at 2.27, 2.05, and 1.81 eV, which are assigned to 2D perovskites with n=2, 3, and 4, respectively. As discussed above, the depth-dependent GIWAXS data also confirmed this graded distribution. The top-down 297 structure information shows that the 2D perovskites with small n value $(n=2)$ are 298 prone to be existed near the surface. Due to graded distribution of BA^+ in the 2D perovskite region (Figure 1c), the energy diagram at the perovskite/HTL interface can 300 be estimated³¹. As shown in Supplementary Fig. 10b, the energy diagram of perovskites with gradient energy structure distribution for the 2mg/ml BABr treated case is depicted. Compare to pure 3D perovskite device, the graded 2D perovskites lead to a graded energy level transition from bulk 3D perovskite to 2D perovskite. The energy level shift is not linear, envisioned from BA^+ spatial distribution. We can expect the energy level gradient is smooth close to bulk perovskite, but the gradient is much faster when reaching the spiro-OMeTAD HTL side. Therefore, the aforementioned graded 2D perovskite layer can be regarded as of the same function as the graded window layer in traditional thin film solar cells, which provide a potential barrier for the electrons 32 . The electrons moving towards perovskite top surface (where the trap state density is higher than that in the bulk) will be reflected back close to the interface. This energy level alignment thus will further eliminate the surface recombination effectively. In the meantime, the mildly graded valance band energy level alignment transition can also facilitate efficient hole transport from perovskite to HTM.

Photoluminescence (PL) and time-resolved PL (TRPL) measurements were conducted for the various perovskite films to examine the defect passivation effect (Supplementary Fig. 12). For the DGPF perovskite films, in addition to a significant PL intensity enhancement, we observed a slight blue-shift of the PL peaks, which agree with the scenario of the Br substitution to Γ , and the resulted shrinkage of the 3D crystal lattice. The carrier lifetime of control perovskite film was significantly increased in the self-passivated DGPF perovskite films. All DGPF perovskite films exhibit a long exponential PL decay tail with PL lifetimes above 1 µs (in particular, a PL lifetime of 1.86 µs was obtained for 2-BABr sample), contrasting the shorter one (0.76 µs) for the control perovskite film. This is consistent with the higher voltages shown in Fig. 3c for DGPF perovskite devices, in which the defects were effectively passivated³³. Furthermore, we measure the external photoluminescence quantum efficiency (PLQE) for the perovskite films with different contacts. The geometry of the PL measurement is shown in Supplementary Fig. 13, in which the light excitation either from top side or bottom sides. Here we used an incident laser with wavelength of 485 nm, which has a penetration depth less than 100 nm according to Snell's law, which implies that we can mainly collect the PL signal near the top surface of 332 perovskite film under the front excitation³⁴. The PLQE of DGPF perovskite film deposited on the glass reaches a value of 13.58%, whereas only 4.65% for control perovskite film. When the presence of charge selective contacts (electrons or holes), the PLQE values for both control and DGPF perovskite films decrease, which can be ascribed to the quench effect and introduced non-radiative channels at the contact 337 interface³⁵. We again observe that the DGPF approach enable a less notable reduction in PLQE upon presence of selective contacts. In the case of light excitation from either top or bottom, the higher PLQEs for the DGPF perovskite samples suggest that optoelectronic properties of perovskite film as well as its related interfaces and surfaces can be optimized via DGPF method.

Highly sensitive photothermal deflection spectroscopy (PDS) technique is conducted to study the sub bandgap/trap state absorption and energetic disorder in these samples . A decrease of sub-bandgap absorption determined by the PDS is clearly seen in the DGPF perovskite films, indicating reduced sub-bandgap states (trap states). The presence of electronic sub-bandgap trap states is one of the origins 347 of non-radiative recombination pathways $37,38$. The internal passivation derived from 2D perovskite participation in the final DGPF perovskite film can effectively suppress non-radiative recombination to incur minimal voltage losses. PDS result comes with a characteristic Urbach energy. The Urbach energies, estimated from the PDS spectra are 20.55, 19.7, 19.9, and 23.21 meV for the sample treated with the BABr concentration of 0 mg/ml, 1 mg/ml, 2 mg/ml, and 5 mg/ml, respectively (Supplementary Fig. 14). The lower Urbach energy indicates a lower level of electronic disorder in the perovskite films with a low concentration of BABr treatment, 355 which agrees with the enhancement of V_{OC} ³⁹. When increasing the BABr concentrations to 5 mg/ml, we observe a gentle band-edge absorption rise, indicating increased energy disorder. As the inherent Urbach energy in 2D perovskite is higher compared to 3D counterparts, this is expected and also consistent with the decreasing device performance when treating with higher concentration of BABr. The PDS result of 2D perovskites is shown in Supplementary Fig. 15, which shows the Urbach energy of 2D perovskite is 38.4 meV.

We further performed electronic structure calculations based on density functional theory (DFT) calculations to investigate the passivation mechanism at BA/perovskite interface. The surface terminated with (110) plane was used for the calculations. Charge density calculations based on the DFT were performed to characterize how amine, including BA molecule, can passivate the Cs_{0.125}FA_{0.875}Pb(I_{0.85}Br_{0.15})₃ surfaces. The anti-site defect is modeled, such as Pb_{Br} or 368 Pb_I, known as deep-level defects and the most detrimental defects in perovskite solar cells⁴⁰. As illustrated in Supplementary Fig. 16, the charge distribution is localized around the anti-site defect site, which can produce the recombination center and capture the carriers. After interaction with BA molecule, we first find that the nitrogen (N) will bond with Pb atoms and then the previous anti-site defect can be passivated, shown in Supplementary Fig. 16c, like the perfect surface without defect indicating by

Supplementary Fig. 16b. Without the dopant BA, the localized electron distribution is observed clearly in Supplementary Fig. 16a. The adsorption of BA will make the charge distribution delocalized, indicating that the trap states caused by anti-site defect are passivated. Trap density of states (tDOS) of control and DGPF devices are further examined, showing a much lower tDOS in DGPF devices, which is consistent with DFT calculation (Supplementary Fig. 17).

380 The effectiveness of the DGPF approach has validated in more perovskite 381 systems. In double cation $MA_{0.7}FA_{0.3}PbI₃$ perovskite system, XRD measurement was 382 conducted to analysis the crystal structure of the formed DGPF perovskite film 383 (Supplementary Fig. 18). The perovskite film shows slight peak shift towards higher 384 2θ degrees, which is consistent with the findings from quaternary RbCsMAFA 385 perovskite system. The GIWAXS results in Supplementary Fig. 19 clearly show the 386 2D diffractive peaks for the BABr-treated samples. The formed 2D perovskite top 387 layer consists of layered 2D perovskites with different n values ($n=2 \& n=3$). The 388 device performance based on these narrower-bandgap perovskite $(MA_{0.7}FA_{0.3}PbI₃)$ 389 $E_g=1.55$ eV) are shown in Supplementary Fig. 20. The best-performing 390 MA_{0.7}FA_{0.3}PbI₃ PSC with 2 mg/ml BABr post-treatment (E_g =1.56 eV) exhibits a V_{OC} 391 of 1.161 V, a J_{SC} of 22.95 mA/cm², and a FF of 77.67%, featuring a high PCE of 392 20.67%. For comparison, the control pure 3D device has a lower PCE of 18.59%. The 393 significantly enhanced V_{OC} for the DGPF PSCs is associated with a significantly 394 reduced V_{OC} deficit, i.e., W_{OC} of 0.40V.

395 This method was also tested in wide-bandgap (WBG) mixed-cation Pb PSCs, 396 which has the significance of being potentially an ideal WBG subcell for tandem 397 perovskite PSCs towards higher efficiency^{41, 42}. By means of DGPF approach, the 398 best-performing wide-bandgap $FA_{0.8}Cs_{0.2}Pb(I_{0.7}Br_{0.3})$ ₃ PSC (E_g =1.73 eV) has a PCE of 399 18.09% with a W_{OC} of 0.48 V and an outstanding V_{OC} of 1.26 V (Supplementary Fig. 400 . 21) ⁴³. This is again one of the highest V_{OC} , and lowest W_{OC} in ~1.73 eV bandgap 401 PSCs, to our knowledge ⁴⁴. Hysteresis analysis of representative PSCs based on 402 various optical bandgaps is shown in Supplementary Fig. 22 and summarized in 403 Supplementary Table 4. Devices after incorporating BABr exhibit lower *J-V* hysteresis compared to the control pure 3D PSC device, which is consistent with the scenario that larger BA moieties mitigate or even prohibit ion migration and reduce defect mentioned above. The data of voltage loss analysis in perovskite devices with different bandgaps were summarized in Table 1.

408 We further proved the effectiveness of DGPF approach in a \sim 1.53 eV perovskite 409 system $(Cs_{0.03} (FA_{0.97} MA_{0.03})_{0.97} Pb(I_{0.97} Br_{0.03})$ with a modified SnO₂ QDs ETL. A 410 champion PCE up to 23.78% (average PCE: $23.24 \pm 0.33\%$, certified PCE: 23.09% , 411 Figure S27) with a maximum V_{OC} of 1.210 V (W_{OC} as low as 0.326 V) was achieved, as shown in Fig. 3d. The bandgap of perovskite was calculated through the combination of EQE and UV-vis absorption spectra (see Supplementary Fig. 23, 24). More details can be found in Supplementary Fig. 25-27 and Supplementary Table 7. To evaluate the $\Delta V_{\text{OC,nr}}$, we measured the EQE_{EL} for a complete PSC device operating as a LED in forward voltage bias, as shown in Fig. 3f. The DGPF device exhibited an 417 EQE_{EL} up to 5.78% at an injection current equal to J_{SC} (24.57 mA/cm²), 418 corresponding to a $\Delta V_{\text{OC,nr}}$ of 74 mV, which agreed well with the estimated value from 419 *W*_{OC}. To the best of our knowledge, 0.326 V *W*_{OC} is among the lowest in all reported perovskite systems.

In addition to device performance, the operational stability of PSCs is also vital for PSC technology. We first investigated the long-term stability of control and DGPF PSCs (non-encapsulated) under dark storage in the ambient conditions with 30% relative humidity (RH) (Supplementary Fig. 28). The DGPF PSCs showed significantly enhanced resistivity to humidity, virtually no PCE degradation after 45 days. This is attributed to the improved hydrophobicity of perovskite structure after introducing large organic cation (BA). We further studied the stability of encapsulated 428 device under continues simulated sunlight illumination $(\sim 35 \degree C)$ at open-circuit condition. The DGPF PSCs showed much slower performance degradation compared to pure 3D PSCs. The encapsulated DGPF PSCs retained 62% of the initial PCE after 800 h illumination, while the control 3D PSCs only retain the 25% of the original PCE under the same conditions (Fig. 4). All the device parameters recorded during the stability test (Supplementary Fig. 29a and b), are shown in Supplementary Table 5 and

6. 'Burn-in' exponential degradation regime was clearly observed in both types of 435 devices, which is a common phenomenon for PSCs and organic solar cells $25, 45, 46$. More specifically, both types of PSCs experienced a faster performance degradation process (around 100 h), followed by a slower steady degradation. For the 438 encapsulated DGPF PSCs, the T_{80} (i.e. lose 20% initial PCE) post burn-in lifetime is 439 700 h under 0.8-sun illumination. However, the T_{80} post burn-in lifetime for pure 3D 440 PSC devices are significantly shorter at \sim 300 h. To exclude the effects of interface layers (particularly the spiro-OMeTAD HTM) and electric load (under maximum power point (MPP) or OC) on the device operational stability, we fabricated perovskite devices with a planar p-i-n structure (Supplementary Fig. 30a and b) and performed long-term stability test of encapsulated devices illuminated under 445 continues 1-sun irradiation by LED lamp at a temperature of $~60^\circ$ C in air condition 446 as shown in Fig. $4b^{45}$. At MPP condition, we found that both control and DGPF devices showed obviously decreased degradation rates compared that at OC, which can be ascribed to role of excess charge carrier. Finally, our DGPF devices can retain 91% of initial efficiency after 516 h of continuous illumination operation in ambient air conditions. In comparison, the control device only retained 16% of the original PCE under the same conditions.

In summary, we developed a simple DGPF self-passivation strategy for high performance PSCs, which simultaneously achieved both bulk and interface 2D perovskite passivation of the PSCs. The DGPF strategy dramatically boost the PCE of 455 1.63 eV quaternary-cation PSCs to 21.54% , with a superb V_{OC} of 1.24 V; we further 456 improved the PCE up to 23.78% (certified 23.09%) with the maximum V_{OC} of 1.21 V 457 in a \sim 1.53 eV perovskite system, i.e. W_{OC} as low as 0.326 V. Non-radiative recombination losses in perovskite materials and devices can be reduced to as low as $\,$ 74 mV (from EQE_{EL} measurement), one of the lowest reported to date. The method is universally applicable to PSCs of different bandgaps. Moreover, significantly enhanced operation stability is achieved with the simultaneous 2D perovskite passivation in bulk and interfaces. The DGPF approach paves the way to further approach the theoretical PSC efficiency limit via the elimination of non-radiative

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Data availability

The data that support the plots within this paper and other findings of this study are available from the corresponding author upon reasonable request

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Author contributions

G.L., G.Y. and Y.Y. proposed the idea and designed the experiment. G.Y. and Z.R. fabricated and characterized perovskite solar cells. Z.R., K.L. and Q.L. prepared and characterized the devices for the efficiency certification of PSCs. G.Y. conducted SEM, AFM, XRD, and PL measurements. X.L. and M.Q. carried out GIWAXS measurement and analyzed the results. W.D. and H.W. conducted the EL measurement and discussed the radiative and non-radiative recombination loss analysis. Y.C. performed DFT calculations on the BA molecule passivation under the supervision of T.S. and X.W. B.G. and J.H. helped to measure the Ultrasensitive EQE. D.L. and S.L. contributed to the PLQY measurement. J.L., H.W., and F.Y. carried out the UPS and absorption measurements. H.Y. and S.K.S contributed to the photothermal deflection spectroscopy data. H.Z. contributed to the ToF-SIMS result analysis. Y.Z performed the HRTEM measurement and analyzed the results under the supervision of J.W.. G.L., G.F., Y.Y., G.Y., Z.R., K.L., and X.L. prepared, revised, and finalized the manuscript. All the authors discussed the results and commented on the manuscript.

Competing financial interests

- The authors declare no competing financial interests.
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Methods

Materials and Methods

- 644 Preparation of RbCsMAFA (Rb_{0.05}Cs_{0.05}[(FA_{0.83}MA_{0.17})]_{0.9}Pb(I_{0.83}Br_{0.17})₃)
- 645 First, a nonstoichiometric precursor solution for $(FA_{0.83}MA_{0.17})Pb(I_{0.83}Br_{0.17})$
- 646 was prepared by dissolving 1.1 M PbI₂ (TCI), 1 M FAI (Dyesol), 0.22 M PbBr₂, and

647 0.2 M MABr (Dyesol) in 1 mL of a 4 : 1 (v/v) mixture of anhydrous DMF and DMSO. 648 (Please note the volume changes upon dissolving these salts) 40 μ L of 1.5 M CsI 649 (Alfa Aesar) pre-dissolved in 1mL DMSO and 40 µL of 1.5 M RbI (Alfa Aesar) 650 pre-dissolved in 1mL of a 4 : 1 (v/v) mixture of anhydrous DMF and DMSO were 651 then added to the as-prepared $(FA_{0.83}MA_{0.17})Pb(I_{0.83}Br_{0.17})$ solution, yielding a 652 quadruple cation perovskite composition of 653 Rb_{0.05}Cs_{0.05}[(FA_{0.83}MA_{0.17})]_{0.9}Pb(I_{0.83}Br_{0.17})₃. The quadruple perovskite solution was 654 stirred for 6 at room temperature and then filtrated using a 0.45 µm filter before use. 655 For RbCsMAFA film deposition, 50 µL of the perovskite precursor solution was 656 spin-coated onto the substrates at 1000 and 5000 rpm for 10 and 20 s, respectively. 657 105 µL chlorobenzene was dropped to the perovskite film at 25 s of the spinning 658 process. The perovskite films were then put on a hot plate at $100 \degree C$ for 60 min.

659

660 Preparation of MA_0 ₇ FA_0 ₃ PbI_3

661 The $MA_{0.7}FA_{0.3}PbI₃$ precursor solutions were contained 1.25 M 662 (PbI2:MAI:FAI=1:0.7:0.3) in a mixed solvent of DMF and DMSO (volume radio: 4:1). 663 12 mg Pb(SCN)₂ (Sigma-Aldrich) was then added into 1mL $MA_{0.7}FA_{0.3}PbI_3$ precursor 664 solutions. For $MA_{0.7}FA_{0.3}PbI_3$ film deposition, 50 µL of the perovskite precursor 665 solution was spin-coated onto the substrates at 1000 and 4000 rpm for 5 and 30 s, 666 respectively. 300 µL chlorobenzene was dropped to the perovskite film at 13-15 s of 667 the spinning process. Then the as-deposited film was annealed at 65 \degree C for 2 min and 668 then 100 ºC for 10 min.

669

670 Preparation of $FA_{0.8}Cs_{0.2}Pb(I_{0.7}Br_{0.3})_3$

671 The $FA_{0.8}Cs_{0.2}Pb(I_{0.7}Br_{0.3})$ precursor solutions were contained 0.8 M FAI, 0.2 672 M CsI, 0.55 M PbI₂, 0.45 M PbBr₂, and 0.55% M Pb(SCN)₂ in a mixed solvent of 673 DMF and DMSO (volume radio: 3:1). For $FA_{0.8}Cs_{0.2}Pb(I_{0.7}Br_{0.3})$ film deposition, 50 674 µL of the perovskite precursor solution was spin-coated onto the substrates at 1000 675 and 4000 rpm for 5 and 30 s, respectively. 300 µL chlorobenzene was dropped to the 676 perovskite film at 13-15 s of the spinning process. The as-prepared film was annealed 677 at 65 °C for 2 min and then 100 °C for 10 min.

678

679 Preparation of $CS_{0.03}(FA_{0.97}MA_{0.03})_{0.97}Pb(I_{0.97}Br_{0.03})_{3}$

680 The $Cs_{0.03}(FA_{0.97}MA_{0.03})_{0.97}Pb(I_{0.97}Br_{0.03})_3$ precursor solution was prepared 681 with the mixed powders of FAI: MABr: MACl: PbBr₂: PbI₂ (molar ratio: 682 1.41:0.04:0.4:0.04:1.47) in the mixture of DMF: DMSO (4:1, v:v), blended with 3% 683 volume ratio of CsI (1.5 M) stock solution. For $Cs_{0.03} (FA_{0.97} MA_{0.03})_{0.97} Pb(I_{0.97} Br_{0.03})_3$ 684 film deposition, 50 μ L of the perovskite solution was spin-coated onto the SnO₂ 685 coated ITO substrate at 1000 and 6000 rpm for 10 and 30s, respectively. 150 µL 686 chlorobenzene was dropped onto the perovskite film at 15-20 s of high-speed 687 spin-coating process. The as-prepared films were annealed at 120 ºC for 1 h in the 688 ambient atmosphere with \sim 20% RH.

689 For Dimensionally Graded Passivation method, 100 μL of BABr-IPA solution 690 (the concentrations ranged from 1 to 5 mg/mL) was spin-coated on the as-prepared perovskite films at 5000 rpm for 30 s. Then the perovskite films were annealed at 100

ºC for 10 min.

Perovskite solar cells fabrication

N-i-p solar cells: The indium tin oxide (ITO)–coated glass was sequentially cleaned using deionized water, acetone, and ethanol. All substrates were further 696 cleaned by UV-ozone for 15 min before deposition of $SnO₂ ETL$. 30 nm $SnO₂ QD$ ETL was deposited on the cleaned ITO substrate by spin-coating as-prepared colloidal $\,$ SnO₂ OD solution.¹⁴ Following, the as-deposited SnO₂ OD ETL was annealed on a hot plate at 200 °C for 1 h in air. The mixed-cation perovskite was deposited via a one-step spin-coating procedure as mentioned above. 20 μL spiro-OMeTAD solution containing 72.3 mg spiro-OMeTAD (Lumitech), 28.8 μL tert-butylpyridine (t-BP, Sigma-Aldrich), 17.5 μL bis(trifluoromethanesulfonyl)imide (Li-TFSI, Sigma-Aldrich) solution (520 mg in acetonitrile), and 1 mL chlorobenzene was spin-coated onto the perovskite layer at 3000 rpm for 20 s. Finally, a thickness of 80 nm Au was deposited by thermal evaporation.

P-i-n solar cells: The PTAA solution (2 mg/mL in toluene) was spin-coated onto 707 the perovskite layer at 5000 rpm for 30s and annealed at 100 °C for 10 min. 1.63 eV perovskite layer was deposited on PTAA layer with the same method based on 709 one-step approach. Then, 30-nm-thick C_{60} layer (electron transport layer) and 710 12-nm-thick $SnO₂$ layer (buffer layer) were deposited by thermal evaporation and atomic layer deposition, respectively. Finally, 100-nm-thick Cu was thermal evaporated as top metal electrode.

Solar cell characterization

The current-voltage (*J*-*V*) characteristics of the devices were measured by using a Keithley 2400 Source Meter under standard AM 1.5 G Simulator (SS-F5, Enli Technology Co. Ltd., Taiwan), and the light intensity was calibrated by a standard SRC-2020 Si reference cell. The *J*-*V* curves were obtained from the range of 1.3 V to -0.1 V with a scan speed of 100 mV/s from both reverse and forward scan direction. 720 The active area of device is 0.09 cm^2 , a mask with an aperture area of 0.0625 cm^2 was used to define device area. The stabilized output of the devices was measured by recording the current output of the illuminated device while holding it at a constant voltage near the maximum power point extracted from the *J-V* curve.

Solar cell certification

Device certification was conducted by Enli Tech. Optoelectronic Calibration Lab., a photovoltaic certification laboratory accredited by Taiwan Accreditation Foundation (Accreditation Criteria: ISO/IEC 17025:2005).

Photo-stability test

The devices are kept under a white light-emitting diode (LED) array with 0.8 sun intensities, which was calibrated using a standard silicon solar cell (KG 5). The 732 encapsulated devices were exposed to below 20% relative humidity at \sim 35 °C.

External quantum efficiency (EQE)

The EQE measurements of photovoltaic device were carried out from 300 to 850 nm using a QE-R 3011 system (Enli Tech, Taiwan). X-ray diffraction (XRD) and Grazing-incidence wide-angle X-ray scattering (GIWAXS) characterization The crystal structure and phase of the materials were characterized using an XRD 741 (Rigaku SmartLab X-ray diffractometer) with Cu K α radiation under operation 742 conditions of 40 kV and 40 mA (The θ -2 θ scan mode from 10° to 70° in a step of 0.01°). The GIWAXS measurements were carried out with a Xeuss 2.0 SAXS/WAXS laboratory beamline using a Cu X-ray source (8.05 keV, 1.54 Å) and a Pilatus3R 300K detector. The incidence angle is 0.3°. The perovskite films for XRD and 746 GIWAXS characterizations were deposited on on $SnO₂$ -coated ITO substrates. Scanning electron microscopy (SEM) The morphologies and microstructures were investigated by using a TESCAN MAIA3 field emission scanning electron microscopy. The perovskite films for SEM 751 measurement were prepared on $SnO₂$ -coated ITO substrates. Atomic force microscopy (AFM) Bruker NanoScope 8 atomic force microscope was used to measure height and phase profile of perovskite films in the tapping mode. The perovskite films for AFM 757 measurement were prepared on $SnO₂$ -coated ITO substrates. Photothermal deflection spectroscopy (PDS) For PDS measurement, the perovskite film was deposited on quartz substrate and then immersed into Fluorinert FC-72 from 3M Corporation. A monochromatic light beam was modulated at 13 Hz by a mechanical chopper to excite the perovskite films from the quartz side. A laser was at the perpendicular side so that it was deflected periodically. A position detector, connected with a lock-in amplifier, was placed on the other side so that the beam deflection signal was measured. The time-of-flight secondary-ion mass spectroscopy (ToF-SIMS) The perovskite films were deposited on the ITO substrates for ToF-SIMS measurement. The ToF-SIMS measurements (Model TOF-SIMS V, ION-TOF GmbH) 770 were conducted with the pulsed primary ions from a $Cs⁺$ (3 keV) liquid-metal ion gun 771 or C_{60} (10 keV) for the sputtering and a Bi⁺ pulsed primary ion beam for the analysis (25 keV). Time-resolved photoluminescence and photoluminescence spectra Photoluminescence measurements of perovskite film on glass were conducted by using an Edinburgh FLSP920 spectrophotometer installed with the excitation source of 485 nm picosecond pulsed diode laser in the average power of 0.15 mW.

Ultraviolet-visible (UV-Vis) absorption spectra

The absorption spectra of the perovskite films were measured by an UV-vis spectrophotometer (CARY5000, Varian, Australia) in a wavelength range at 300-850 nm at room temperature.

Ultraviolet photoelectron spectroscopy (UPS)

The samples for UPS measurements were made by depositing perovskite films on the ITO conductive substrates. Then the UPS measurement was performed using a XPS/UPS system (Thermo Scientific, Escalab 250Xi).

Photoluminescence quantum efficiency (PLQE)

The PLQE of perovskite films was measured using an integrating sphere 791 (Edinburgh instruments) with a 485-nm excitation laser (-125 mW/cm^2) in open-air conditions.

794 External quantum efficiency of the electroluminescence (EQE_{EL})

795 The EQE_{EL} of the solar cells was determined by measuring the emitted photons of devices in all directions through an integrated sphere by using a calibrated spectrometer (QE Pro, Ocean Optics), under a constant current density provided by a Keithley 2400 source measure unit. The devices were left at room temperature in open-air conditions.

Trap density of states (tDOS)

Admittance spectra were measured by using an Agilent E4980A meter with an alternating voltage of 20 mV. The frequency-dependence of the capacitance was recorded from 1 kHz to 2000 kHz with zero bias in the dark.

Transmission electron microscope characterization (TEM)

Transmission electron microscopy (TEM) lift-out samples were prepared via focused ion beam (FIB) polishing in a TESCAN GAIA3 FIB-SEM. A covering layer of 1.5 μm thick platinum was deposited by electron beam. The TEM lamella was extracted by FIB with an ion beam of accelerating voltage of 30 kV and current of 7 nA and welded to a TEM copper grid by platinum. After that, the TEM lamella was polished to about 300 nm thick with accelerating voltage of 30 kV and current of 100 pA. Finally, it was thinned to electron transparency with accelerating voltage of 5 kV and current of 25 pA and accelerating voltage of 2 kV and current of 20 pA. Accelerating voltage for SEM observation and electron beam deposition was kept at 5 kV during the whole process. The TEM lift-out sample was sent into TEM chamber in less than one minute after the sample preparation. TEM observations were carried out by using a JEOL ARM200CF transmission electron microscope equipped with a cold field-emission electron gun and double spherical-aberration correctors (CEOS GmbH) operated at 80 kV.

Density functional theory (DFT) calculations

Figure 1

Figure 2

Figure 3

Figure 4

Note:

^aE_g was derived from the average value of $E_{\rm g}^{\rm IP}$ and $E_{\rm g}^{\rm Tauc}$.

 ${}^{\text{b}}\Delta V_{\text{OC,SQ}}$ was calculated (as a function of bandgap) using detailed balance principle.

^c $\Delta V_{\text{OC,rad}}$ =Eg/q- $V_{\text{OC,rad}}$, and this is only available for 1.63 eV perovskites shown in this table.

^d Δ *V*_{OC,nr} was calculated from *W*_{OC} and Δ *V*_{OC,SQ} or Δ *V*_{OC,rad}.